

<b>Notice of References Cited</b>	Application/Control No. 10/829,178		Applicant(s)/Patent Under Reexamination SUDA, TAKASHI	
	Examiner Craig A. Renner		Art Unit 2627	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0120061 A1	06-2004	Yip et al.	360/048
*	B	US-2005/0219734 A1	10-2005	Rothermel et al.	360/075
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	K	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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